

## N- and P-Channel Enhancement-Mode Dual MOSFET

### Features

- ▶ 500V breakdown voltage
- ▶ Independent N- and P-channels
- ▶ Electrically isolated N- and P-channels
- ▶ Low input capacitance
- ▶ Fast switching speeds
- ▶ Free from secondary breakdowns
- ▶ Low input and output leakage

### Applications

- ▶ High voltage pulsers
- ▶ Amplifiers
- ▶ Buffers
- ▶ Piezoelectric transducer drivers
- ▶ General purpose line drivers

### General Description

The Supertex TC1550 consists of a high voltage N-channel and P-channel MOSFET in an 8-Lead SOIC package. This is an enhancement-mode (normally-off) transistor utilizing an advanced vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces a device with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, this device is free from thermal runaway and thermally induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

### Ordering Information

Device	Package Option 8-Lead SOIC 4.90x3.90mm body 1.75mm height (max) 1.27mm pitch	$BV_{DSS}/BV_{DGS}$		$R_{DS(ON)}$ (Max)	
		N-Channel (V)	P-Channel (V)	N-Channel ( $\Omega$ )	P-Channel ( $\Omega$ )
TC1550	TC1550TG-G	500	-500	60	125

-G indicates package is RoHS compliant ('Green')



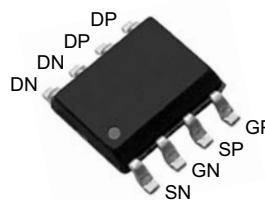
### Absolute Maximum Ratings

Parameter	Value
Drain-to-source voltage	$BV_{DSS}$
Drain-to-gate voltage	$BV_{DGS}$
Gate-to-source voltage	$\pm 20V$
Operating and storage temperature	$-55^{\circ}C$ to $+150^{\circ}C$
Soldering temperature*	$300^{\circ}C$

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability. All voltages are referenced to device ground.

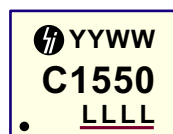
\* Distance of 1.6mm from case for 10 seconds.

### Pin Configuration



**8-Lead SOIC (TG)**  
(top view)

### Product Marking



YY = Year Sealed  
 WW = Week Sealed  
 L = Lot Number  
 \_\_\_\_\_ = "Green" Packaging

**8-Lead SOIC (TG)**

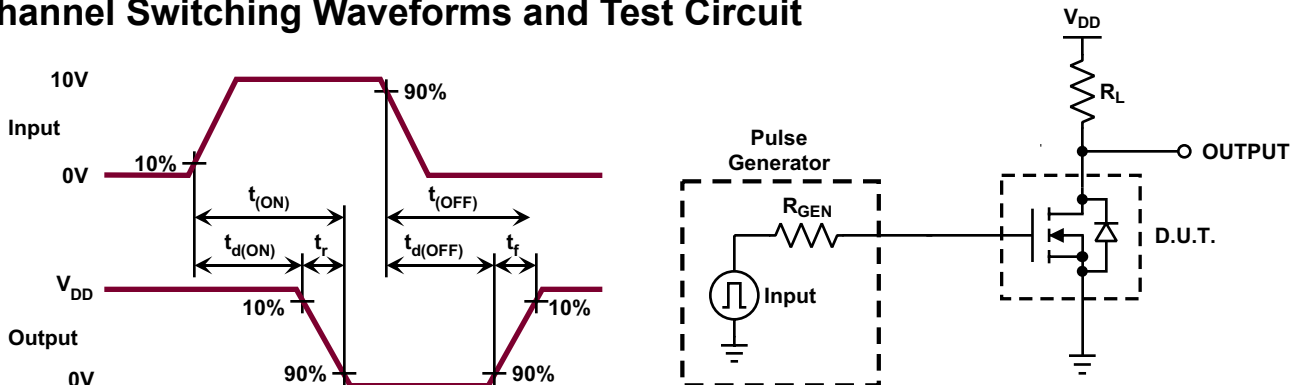
**N-Channel Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Sym	Parameter	Min	Typ	Max	Units	Conditions
$BV_{DSS}$	Drain-to-source breakdown voltage	500	-	-	V	$V_{GS} = 0V, I_D = 1.0mA$
$V_{GS(th)}$	Gate threshold voltage	2.0	-	4.0	V	$V_{GS} = V_{DS}, I_D = 1.0mA$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with temperature	-	-3.8	-5.0	mV/°C	$V_{GS} = V_{DS}, I_D = 1.0mA$
$I_{GSS}$	Gate body leakage current	-	-	100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
$I_{DSS}$	Zero gate voltage drain current	-	-	10	$\mu A$	$V_{GS} = 0V, V_{DS} = \text{Max Rating}$
		-	-	1.0	mA	$V_{DS} = 0.8 \text{ Max Rating}, V_{GS} = 0V, T_A = 125^\circ\text{C}$
$I_{D(ON)}$	On-state drain current	-	100	-	mA	$V_{GS} = 5.0V, V_{DS} = 25V$
		150	350	-		$V_{GS} = 10V, V_{DS} = 25V$
$R_{DS(ON)}$	Static drain-to-source on-state resistance	-	45	-	$\Omega$	$V_{GS} = 5.0V, I_D = 50mA$
		-	40	60		$V_{GS} = 10V, I_D = 50mA$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with temperature	-	1.0	1.7	%/°C	$V_{GS} = 10V, I_D = 50mA$
$G_{FS}$	Forward transconductance	50	100	-	mmho	$V_{DS} = 25V, I_D = 50mA$
$C_{ISS}$	Input capacitance	-	45	55	pF	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0MHz$
$C_{OSS}$	Common source output capacitance	-	8.0	10		
$C_{RSS}$	Reverse transfer capacitance	-	2.0	5.0		
$t_{d(ON)}$	Turn-on delay time	-	-	10	ns	$V_{DD} = 25V, I_D = 150mA, R_{GEN} = 25\Omega$
$t_r$	Rise time	-	-	15		
$t_{d(OFF)}$	Turn-off delay time	-	-	10		
$t_f$	Fall time	-	-	10		
$V_{SD}$	Diode forward voltage drop	-	0.8	-	V	$V_{GS} = 0V, I_{SD} = 500mA$
$t_{rr}$	Reverse recovery time	-	300	-	ns	$V_{GS} = 0V, I_{SD} = 500mA$

**Notes:**

1. All DC parameters 100% tested at 25°C unless otherwise stated. (Pulsed test: 300µs pulse at 2% duty cycle.)
2. All AC parameters sample tested.

**N-Channel Switching Waveforms and Test Circuit**



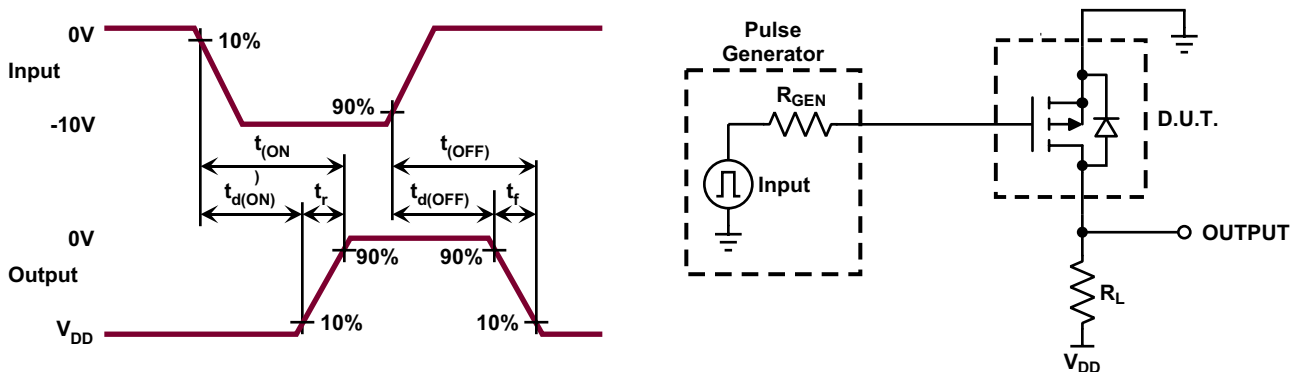
**P-Channel Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Sym	Parameter	Min	Typ	Max	Units	Conditions
$BV_{DSS}$	Drain-to-source breakdown voltage	-500	-	-	V	$V_{GS} = 0V, I_D = -1.0mA$
$V_{GS(th)}$	Gate threshold voltage	-2.0	-	-4.5	V	$V_{GS} = V_{DS}, I_D = -1.0mA$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with temperature	-	3.5	6.0	mV/°C	$V_{GS} = V_{DS}, I_D = -1.0mA$
$I_{GSS}$	Gate body leakage current	-	-	100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
$I_{DSS}$	Zero gate voltage drain current	-	-	-10	$\mu\text{A}$	$V_{GS} = 0V, V_{DS} = \text{Max Rating}$
		-	-	-1.0	mA	$V_{DS} = 0.8 \text{ Max Rating}, V_{GS} = 0V, T_A = 125^\circ\text{C}$
$I_{D(ON)}$	On-state drain current	-	-90	-	mA	$V_{GS} = -5.0V, V_{DS} = -25V$
		-100	-240	-		$V_{GS} = -10V, V_{DS} = -25V$
$R_{DS(ON)}$	Static drain-to-source on-state resistance	-	85	-	$\Omega$	$V_{GS} = -5.0V, I_D = -5.0mA$
		-	80	125		$V_{GS} = -10V, I_D = -10mA$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with temperature	-	0.85	-	%/°C	$V_{GS} = -10V, I_D = -10mA$
$G_{FS}$	Forward transconductance	25	40	-	mmho	$V_{DS} = -25V, I_D = -10mA$
$C_{ISS}$	Input capacitance	-	40	70	pF	$V_{GS} = 0V, V_{DS} = -25V, f = 1.0MHz$
$C_{OSS}$	Common source output capacitance	-	10	20		
$C_{RSS}$	Reverse transfer capacitance	-	3.0	10		
$t_{d(ON)}$	Turn-on delay time	-	5.0	10	ns	$V_{DD} = -25V, I_D = -100mA, R_{GEN} = 25\Omega$
$t_r$	Rise time	-	8.0	10		
$t_{d(OFF)}$	Turn-off delay time	-	8.0	15		
$t_f$	Fall time	-	5.0	16		
$V_{SD}$	Diode forward voltage drop	-	-0.8	-1.5		
$t_{rr}$	Reverse recovery time	-	200	-	ns	$V_{GS} = 0V, I_{SD} = -100mA$

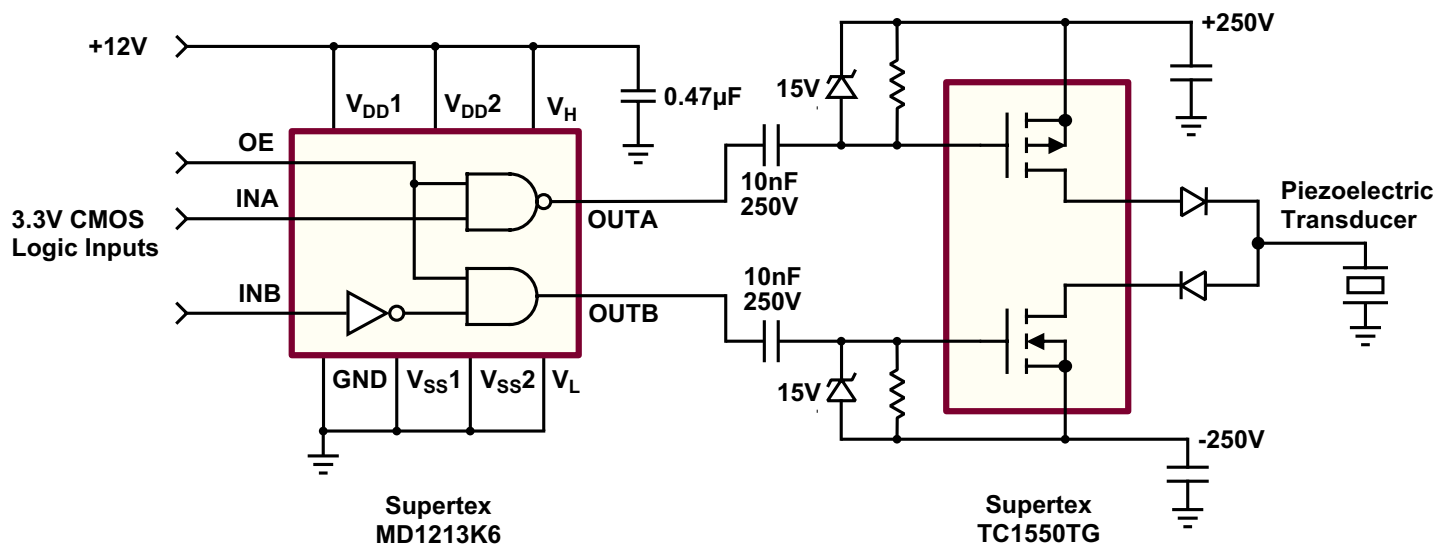
**Notes:**

1. All DC parameters 100% tested at 25°C unless otherwise stated. (Pulsed test: 300µs pulse at 2% duty cycle.)
2. All AC parameters sample tested.

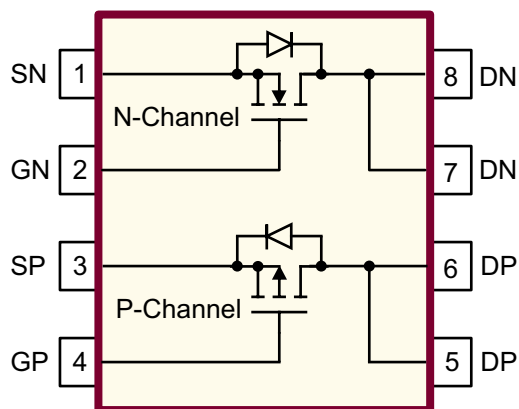
**P-Channel Switching Waveforms and Test Circuit**



Typical Application Circuit

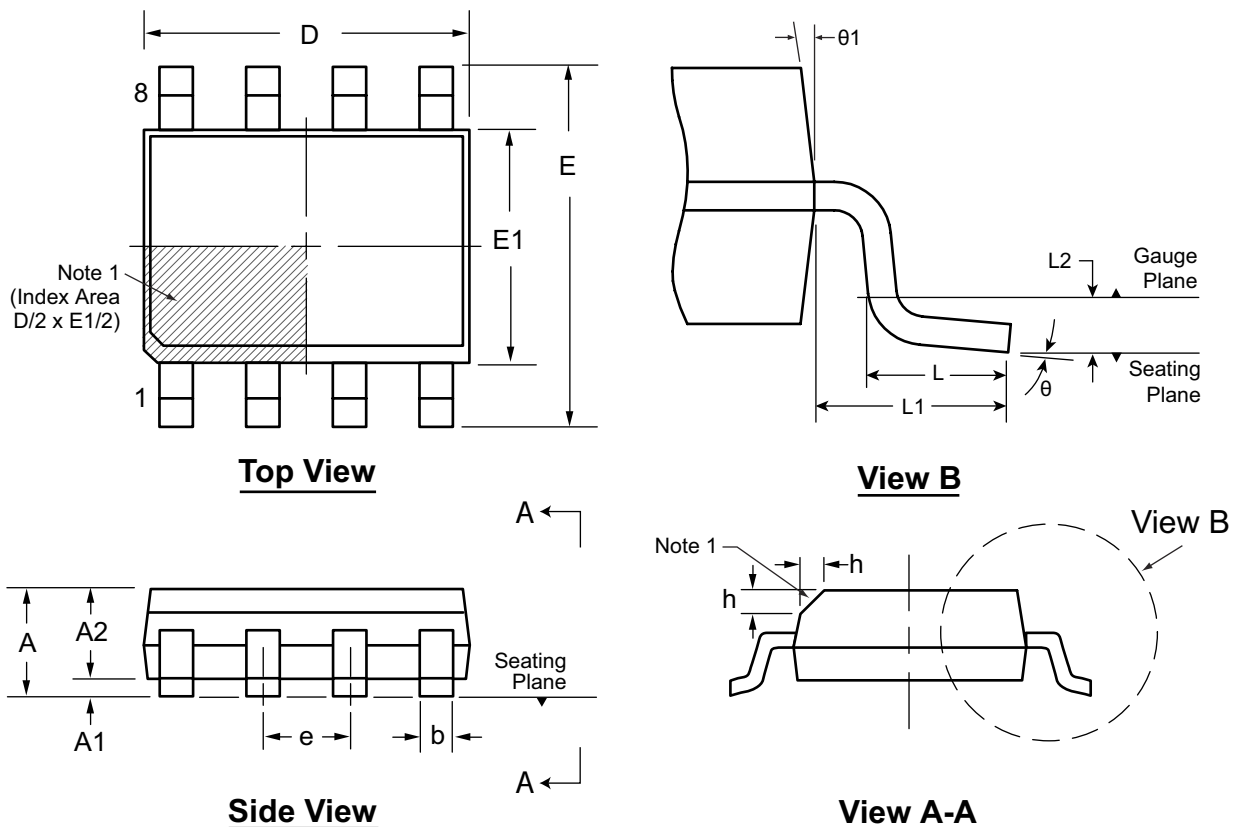


Block Diagram



# 8-Lead SOIC (Narrow Body) Package Outline (TG)

4.90x3.90mm body, 1.75mm height (max), 1.27mm pitch



**Note:**  
 1. This chamfer feature is optional. If it is not present, then a Pin 1 identifier must be located in the index area indicated. The Pin 1 Identifier can be: a molded mark/identifier; an embedded metal marker; or a printed indicator.

Symbol	A	A1	A2	b	D	E	E1	e	h	L	L1	L2	$\theta$	$\theta1$	
Dimension (mm)	MIN	1.35*	0.10	1.25	0.31	4.80*	5.80*	3.80*	1.27 BSC	0.25	0.40	1.04 REF	0.25 BSC	0°	5°
	NOM	-	-	-	-	4.90	6.00	3.90		-	-			-	-
	MAX	1.75	0.25	1.65*	0.51	5.00*	6.20*	4.00*		0.50	1.27			8°	15°

JEDEC Registration MS-012, Variation AA, Issue E, Sept. 2005.  
 \* This dimension is not specified in the original JEDEC drawing. The value listed is for reference only.  
**Drawings are not to scale.**  
**Supertex Doc. #: DSPD-8SOLGTG, Version G090808.**

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information go to <http://www.supertex.com/packaging.html>.)

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